Search	Notes
	1818: IIBIB BIII

Search Motes		

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/048,164	KURIYA ET AL.	
Examiner	Art Unit	
Matthew Heneghan	2134	

	SEARCHED		
Class	Subclass	Date	Examiner
726	29	5/2/2007	мн
	· ·		
<u> </u>			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	aterference arch	5/2/2007	МН

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STIC Fast & Focused Search, see notes	4/23/2007	МН
EAST Update Search, see notes	5/2/2007	МН
ACM, IEEE Searches	5/2/2007	МН
Inventor Search	5/2/2007	МН